



IRF510  
IRF511  
IRF512  
IRF513

T-39-09



### N-Channel Enhancement-Mode Vertical DMOS Power FETs

#### Ordering Information

$BV_{DSS}$ / $BV_{DS}$	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-220
100V	0.6Ω	4.0A	IRF510
60V	0.6Ω	4.0A	IRF511
100V	0.8Ω	3.5A	IRF512
60V	0.8Ω	3.5A	IRF513

#### Features

- Freedom from secondary breakdown
- Low power drive requirement
- Ease of paralleling
- Low  $C_{iss}$  and fast switching speeds
- Excellent thermal stability
- Integral Source-Drain diode
- High input impedance and high gain
- Complementary N- and P-Channel devices

#### Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and negative temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

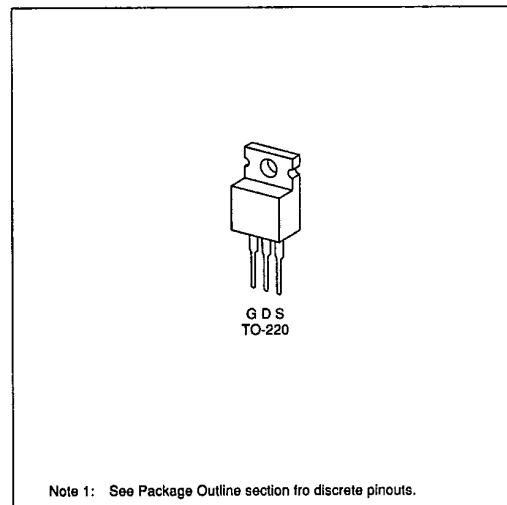
8

#### Applications

- Motor control
- Converters
- Amplifiers
- Switches
- Power supply circuits
- Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

#### Package Options

(Note 1)



G D S  
TO-220

Note 1: See Package Outline section for discrete pinouts.

#### Absolute Maximum Ratings

Drain-to-Source Voltage	$BV_{DSS}$
Drain-to-Gate Voltage	$BV_{DGS}$
Gate-to-Source Voltage	$\pm 20V$
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

\*Distance of 1.6 mm from case for 10 seconds.

T-39-09

**Thermal Characteristics**

Package	$I_D$ (continuous)*	$I_D$ (pulsed)*	Power Dissipation @ $T_C = 25^\circ C$	$\theta_{jc}$ °C/W	$\theta_{ja}$ °C/W	$I_{DR}$	$I_{DRM}^*$
IRF510	4.0A	16.0A	20W	80	6.4	4.0A	16.0A
IRF511	-4.0A	16.0A	20W	80	6.4	4.0A	16.0A
IRF512	3.5A	14.0A	20W	80	6.4	3.5A	14.0A
IRF513	3.5A	14.0A	20W	80	6.4	3.5A	14.0A

\*  $I_D$  (continuous) is limited by max rated  $T_J$ **Electrical Characteristics (@ 25°C unless otherwise specified)**

(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	IRF510, IRF512	100			V	$V_{GS} = 0, I_D = 250\mu A$
		IRF511, IRF513	60				
$V_{GS(th)}$	Gate Threshold Voltage		2.0		4.0	V	$V_{GS} = V_{DS}, I_D = 250\mu A$
$I_{GSS}$	Gate Body Leakage				500	nA	$V_{GS} = \pm 20V, V_{DS} = 0$
$I_{DSS}$	Zero Gate Voltage Drain Current				250	$\mu A$	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
					1000		$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$
							$T_C = 125^\circ C$
$I_{D(ON)}$	ON-State Drain Current	IRF510, IRF511	4.0			A	$V_{GS} = 10V$
		IRF512, IRF513	3.5				$V_{DS} > I_{D(ON)} \times R_{DS(ON)} \text{ Max Rating}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	IRF510, IRF511			0.6	$\Omega$	$V_{GS} = 10V, I_D = 2.0A$
		IRF512, IRF513			0.8		
$G_{FS}$	Forward Transconductance		1.0	1.5		$\text{mS}$	$V_{DS} > I_{D(ON)} \times R_{DS(ON)} \text{ Max Rating}$ $I_D = 2.0A$
$C_{ISS}$	Input Capacitance				150	$\text{pF}$	$V_{GS} = 0, V_{DS} = 25V$ $f = 1 \text{ MHz}$
$C_{OSS}$	Common Source Output Capacitance				100		
$C_{RSS}$	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				20	$\text{ns}$	$V_{DD} = 0.5BV_{DSS}$ $I_D = 2.0A$ $R_S = 50\Omega$
$t_r$	Rise Time				25		
$t_{d(OFF)}$	Turn-OFF Delay Time				25		
$t_f$	Fall Time				20		
$V_{SD}$	Diode Forward Voltage Drop	IRF510, IRF511			2.5	$\text{V}$	$V_{GS} = 0, I_{SD} = 4.0A$
		IRF512, IRF513			2.0		$V_{GS} = 0, I_{SD} = 3.5A$
$t_{rr}$	Reverse Recovery Time				230	$\text{ns}$	$T_J = 150^\circ C, I_{SD} = 4.0A,$ $dI/dt = 100A/\mu s$

Note 1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)

Note 2: All A.C. parameters sample tested.

**Switching Waveforms and Test Circuit**